

- 10:00 D-14 Synthesis and Characterization of Ettringites**
H. Poellmann, *University of Halle, Halle, Germany*
- 10:20 D-33 Oxygen Octahedral Environments in Three-Layer Aurivillius Phases via Combined X-ray and Neutron Powder Diffraction**
E.J. Nichols, S.T. Misture, *Alfred University, Alfred, NY*
- 10:40 Break**
- 11:10 D-95 Bond Length Evolution in 312 and 211 Max Phases from High Temperature Neutron Diffraction and Rietveld Analysis**
N.J. Lane, M.W. Barsoum, *Drexel University, Philadelphia, PA*
S.C. Vogel, *Los Alamos National Laboratory, Los Alamos, NM*
- 11:30 D-12 Quantifying the Extent to which Experimental Pole Intensity Data Determine an Orientation Density Function Explaining the Data**
R. Hielscher, *Technische Universitaet Chemnitz, Germany*
H. Schaeben, *Technische Universitaet Bergakademie Freiberg, Germany*

THURSDAY AM

XRF

ENVIRONMENTAL AND HANDHELD XRF

EVERGREEN B

Chairs: J.A. Anzelmo, Anzelmo & Associates, Inc., Madison, WI
R. Van Grieken, *University of Antwerp, Antwerp, Belgium*

- 8:30 Invited—Title to be announced**
J. Gearheart, Ecology Center, Ann Arbor, MI
- 9:00 F-32 Invited—Assessing the Environment with X-ray Fluorescence**
J. Boman, J.B.C. Pettersson, *University of Gothenburg, Gothenburg, Sweden*
M. Gatari, *University of Nairobi, Nairobi, Kenya*
A. Wagner, *Chalmers University of Technology, Gothenburg, Sweden*
P. Molnár, *Sahlgrenska University Hospital & University of Gothenburg, Gothenburg, Sweden*
- 9:30 F-47 Invited—X-ray Fluorescence Spectrometry in the Environmental Field: A Review of Some Recent Investigations and Applications**
E. Margui, I. Queralt, *Institute of Earth Sciences “Jaume Almera”, CSIC, Barcelona, Spain*
M. Hidalgo, *University of Girona, Girona, Spain*
R. Van Grieken, *University of Antwerp, Antwerp, Belgium*
- 10:00 F-7 Characterization of Silicon Drift Detectors for EDXRF**
R. Redus, T. Pantazis, J. Pantazis, A. Huber, *Amptek, Inc., Bedford, MA*
- 10:20 Break**
- 10:50 F-39 Invited—Micro-XRF Analysis of Metal Alloys: From the Laboratory Calibration Towards In-Situ Analyses**
A.G. Karydas, V. Kantarelou, D. Sokaras, *Institute of Nuclear Physics, NCSR Demokritos, Athens, Greece*
D. Wegrzynek, E-Chinea-Cano, A. Markowicz, *International Atomic Energy Agency (IAEA), Seibersdorf, Austria*
P. Wobrauschek, C. Strelti, *TU Wien Atominstitut, Vienna, Austria*
K. Uhlir, M. Griesser, *Kunsthistorisches Museum, Wien, Austria*